

RESPONSE UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2117

PATENT APPLICATION  
Docket No.: 4591-363  
Client Ref. No.: IB13018-US

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Nam-Jung HER, et al.

Confirmation No.: 5596

Serial No.: 10/803,792 Examiner: Radosevich, Steven D.

Filed: March 17, 2004 Group Art Unit: 2138

For: SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A NUMBER  
OF DATA OUTPUT PINS CAPABLE OF SELECTIVELY PROVIDING  
OUTPUT SIGNALS AND TEST METHOD THEREOF

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT AFTER FINAL REJECTION**

Responsive to the Final Office Action dated May 8, 2007, please amend the application as follows.

Claims begin on page 2.

Remarks begin on page 5.